Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/769,204	CHUNG, CHIA-CHI
Examiner	Art Unit
Heien-ming Lee	2823

	SEARCHED					
Class	Subclass	Date	Examiner			
257	314,315	2411/2	Lee			
257	316,321	1				
257	324,					
438	261,263					
438	262	V	V			
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
		<u> </u>			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST attached (USPAT, USPG, USOCR, EPO, JPO, IBM, Derwent)	6/11/2005	LEE		